Attorney's Docket No.: 14850-002001

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Ares Rosakis, et al. Art Unit: 2877

Serial No.: 10/766,302

Filed: January 27, 2004

Title : OPTICAL CHARACTERIZATION OF SURFACES AND PLATES

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## INFORMATION DISCLOSURE STATEMENT

Dear Sir:

HOV 0 1 2004

Applicants call attention to the attached Information Disclosure Statement and document listed on form PTO-1449.

This filing is being made before the receipt of a first of office action on the merits. No fee is required.

· Consideration of the foregoing and enclosure plus the return of a copy of the enclosed form PTO-1449 with the Examiner's initials in the left column per MPEP 609 are earnestly solicited along with an early action on the merits.

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Substitute Form PTO-1499 U (Modified)

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Attorney's Docket No. 14850-002001

Application No. 10/766,302

Information Disclosure Statement by Applicant (Use several sheets if necessary) Applicant Ares Rosakis, et al.

Filing Date

Group Art Unit 2877

(37 CFR §1.98(b))

January 27, 2004

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6031611	2/29/2000	Rosakis, et al.			
	AB	6469788	10/22/2002	Boyd, et al.			
	AC	6513389	2/4/2003	Suresh, et al.			
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	AF	6781702	8/24/2004	Giannakopoulos, et al.			
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner	Desig.	Document	Publication	Country or		_		lation
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)			
Examiner	Desig.		
Initial	ID	Document	
	AQ	Wikstrom, et al.; Thermoelastic analysis of periodic thin lines deposited on a substrate; 1999; Journal of the Mechanics and Physics of Solids, 47 (1999); pps 1113-1130	
	AR		
	AS		
	AT		

Examiner Signature	Date Considered				
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EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with					
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